## Notice of References Cited Application/Control No. 10/506,814 Examiner BLESSING M. FUBARA Applicant(s)/Patent Under Reexamination LEWIS ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,440,743	08-2002	Kabanov et al.	435/458
	В	US-			
	O	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 98/22517	05-1998	wo	STORCh et al.	
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## **NON-PATENT DOCUMENTS**

	HON-I ATEN BOSSMENTS					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Bronich et al., "Effects of Block Length and Structure of Surfactant on Self-Assembly and Solution Behavior of Block Complexes," in Langmuir, 2000, Vol. 16, 481-489).				
	>					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.